

30V N-Channel Enhancement Mode MOSFET

Description

The AP60N03D uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS} = 30V I_D =60A

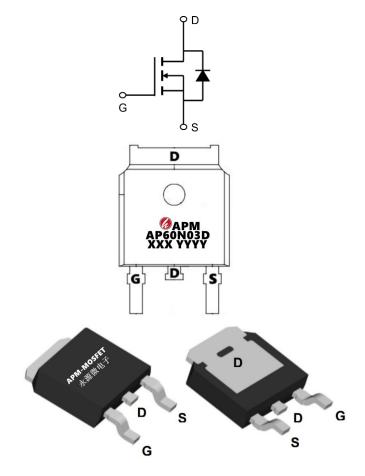
 $R_{DS(ON)} < 8.5m\Omega @ V_{GS}=10V$ (Type: 6.0m Ω)

Application

VBUS

Wireless impact

Mobile phone fast charging



Package Marking and Ordering Information

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Product ID	Pack	Marking	Qty(PCS)		
AP60N03D	TO-252-3L	AP60N03D XXX YYYY	2500		

Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	30	V
VGS	Gate-Source Voltage	±20	V
I₀@Tc=25℃	Continuous Drain Current, V _{GS} @ 10V ¹	60	А
I⊳@Tc=100°C	Continuous Drain Current, V _{GS} @ 10V ¹	40	А
IDM	Pulsed Drain Current ²	92	А
EAS	Single Pulse Avalanche Energy ³	57.8	mJ
IAS	Avalanche Current	34	А
P₀@T₀=25°C	Total Power Dissipation ⁴	29	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R₀JA	Thermal Resistance Junction-ambient ¹	62.5	°C/W
R₀JC	Thermal Resistance Junction-Case ¹	4.32	°C/W



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Electrical Characteristics (Tc=25°C unless otherwise noted)

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit	
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	30	33		V	
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =12A		6.0	8.5	mΩ	
RDS(ON)	Static Drain-Source On-Resistance-	V _{GS} =4.5V , I _D =10A		8.5	13	11152	
VGS(th)	Gate Threshold Voltage		1.0	1.6	2.5	V	
∆VGS(th)	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, $I_D = 250 uA$		-5.8		mV/°C	
IDSS	Drain-Source Leakage Current	V_{DS} =24V , V_{GS} =0V , T_J =25°C			1	uA	
1033	Drain-Source Leakage Current	V_{DS} =24V , V_{GS} =0V , T_{J} =55°C			5		
IGSS	Gate-Source Leakage Current	V_{GS} =±20V , V_{DS} =0V			±100	nA	
gfs	Forward Transconductance	V _{DS} =5V , I _D =15A		9.8		S	
Rg	Gate Resistance	V_{DS} =0V , V_{GS} =0V , f=1MHz		1.7		Ω	
Qg	Total Gate Charge (4.5V)			12.8		nC	
Qgs	Gate-Source Charge	V _{DS} =20V , V _{GS} =4.5V , I _D =12A		3.3			
Qgd	Gate-Drain Charge			6.5			
Td(on)	Turn-On Delay Time			4.5			
Tr	Rise Time	V_{DD} =12V , V_{GS} =10V , R_{G} =3.3 Ω		10.8			
Td(off)	Turn-Off Delay Time	ID=5A		25.5		ns	
T _f	Fall Time			9.6			
Ciss	Input Capacitance			1317			
Coss	Output Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		163		pF	
Crss	Reverse Transfer Capacitance			131			
IS	Continuous Source Current ^{1,6}				46	А	
ISM	Pulsed Source Current ^{2,6}	$V_G=V_D=0V$, Force Current			92	А	
VSD	Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , T」=25℃			1	V	

Note :

1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.

2、 The data tested by pulsed , pulse width $\leq 300 \text{us}$, duty cycle $\leq 2\%$

 3_{\times} The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1mH,IAS=34A

 $4\,{\scriptstyle \sim}\,$ The power dissipation is limited by 150°C junction temperature

5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

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Typical Characteristics

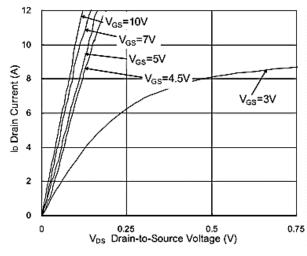


Fig.1 Typical Output Characteristics

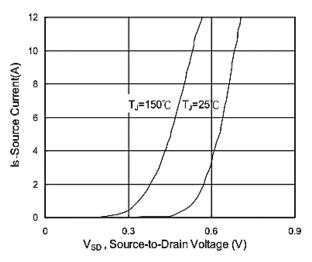


Fig.3 Forward Characteristics of Reverse

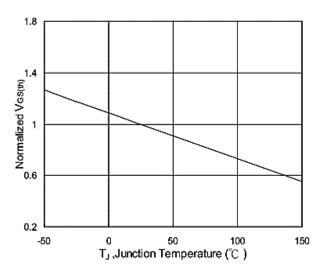


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

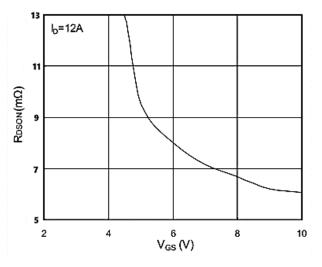


Fig.2 On-Resistance vs. G-S Voltage

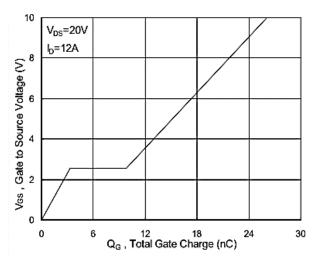
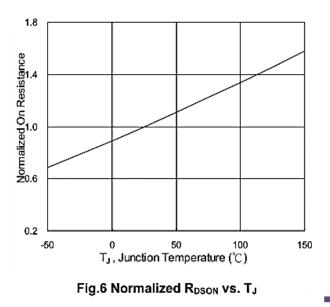


Fig.4 Gate-Charge Characteristics



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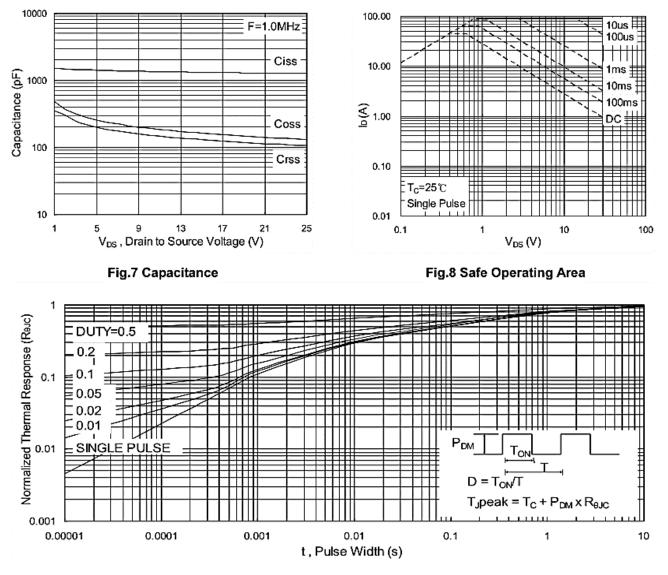


Fig.9 Normalized Maximum Transient Thermal Impedance

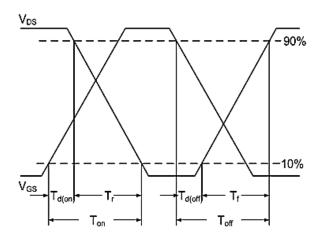


Fig.10 Switching Time Waveform

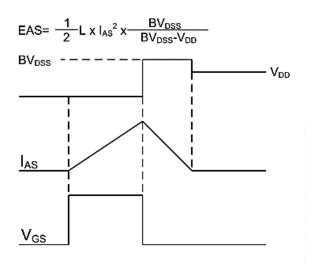


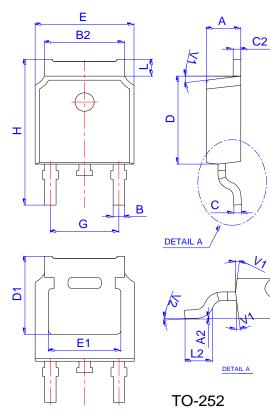
Fig.11 Unclamped Inductive Switching Waveform



<u>AP60N03D</u>

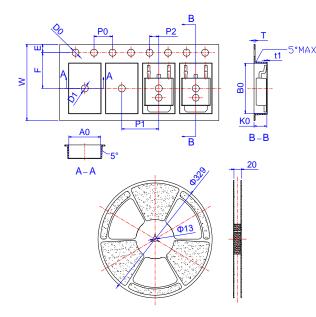
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Package Mechanical Data: TO-252-3L



	Dimensions						
Ref.	Millimeters		Inches				
	Min.	Тур.	Max.	Min.	Тур.	Max.	
A	2.10		2.50	0.083		0.098	
A2	0		0.10	0		0.004	
В	0.66		0.86	0.026		0.034	
B2	5.18		5.48	0.202		0.216	
С	0.40		0.60	0.016		0.024	
C2	0.44		0.58	0.017		0.023	
D	5.90		6.30	0.232		0.248	
D1		5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268	
E1	4.63			0.182			
G	4.47		4.67	0.176		0.184	
н	9.50		10.70	0.374		0.421	
L	1.09		1.21	0.043		0.048	
L2	1.35		1.65	0.053		0.065	
V1		7°			7°		
V2	0°		6°	0°		6°	

Reel Spectification-TO-252



	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
Т	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583



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Edition	Date	Change
Rve1.0	2019/4/10	Initial release
Rve1.1	2022/1/10	Reduce internal RDS

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